

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>		Docket Number (Optional) TWI-11720	Application Number NEW
		Applicant(s) Louis N. Koppel et al.	
		Filing Date HEREWITH	Group Art Unit Unknown

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
JK	*AA	5,042,951	08/27/1991	Gold et al.	356	369	09/19/1989
JK	*AB	5,412,473	05/02/1995	Rosencwaig et al.	356	351	07/16/1993
JK	*AC	5,475,728	12/12/1995	Smith et al.	378	81	08/02/1993
JK	*AD	5,619,548	04/08/1997	Koppel	378	70	08/11/1995
JK	*AE	5,878,106	03/02/1999	Fujiwara	378	79	05/29/96
JK	*AF	5,923,720	07/13/1999	Barton et al.	378	84	06/17/1997
JK	*AG	6,041,098	03/21/2000	Tourianski et al.	378	70	02/02/1998
JK	*AH	6,069,934	05/30/2000	Verman et al.	378	73	04/07/1998
JK							

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
JK	*AI	144 956	11/12/1980	Germany	G01B	15/02		X
JK	*AJ	WO 92/08104	05/14/1992	PCT	G01B	11/24		
JK	*AK	20011116705	04/27/2001	Japan	G01N	23/207	Abstract	
JK								

OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

JK	*AL	K. Sakurai et al., "Fourier Analysis of Interference Structure in X-Ray Specular Reflection from Thin Films," <i>Jpn. J. Appl. Phys.</i> , Vol. 31, 1992, pp. L113-L115.
JK	*AM	K.N. Stoev et al., "Review on grazing incidence X-ray spectrometry and reflectometry," <i>Spectrochimica Acta Part B</i> , Vol. 54, 1999, pp. 41-82.
JK	*AN	N. Wainfan et al., "Density Measurements of Some Thin Copper Films," <i>Journal of Applied Physics</i> , Vol. 30, No. 10, October 1959, pp. 1604-1609.
JK	*AO	J.P. Sauro et al., "Some Observations on the Interference Fringes Formed by X Rays Scattered from Thin Films," <i>Physical Review</i> , Vol. 143, No. 1, March 1966, pp. 439-443.
JK	*AP	K. Sakurai et al., "Analysis of thin films by X-ray scattering at grazing incidence," <i>SPring-8 User Experiment Report No. 2 (1998 A)</i> , March 1999, p. 162.

Examiner <i>Franklin K. Johnson</i>	Date Considered <i>03/03/2004</i>
Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	